

RoHS

COMPLIANT

HALOGEN

P-Channel 30 V (D-S) MOSFET

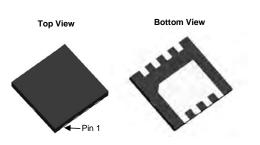
V _{DS}	-30	V	
R _{DS(on),typ}	V _{GS} =10V	11	mΩ
R _{DS(on),typ}	V _{GS} =4.5V	18	mΩ
ID	-45	А	

FEATURES

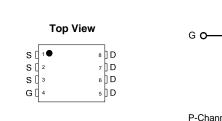
- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET
- Low Thermal Resistance PowerPAK[®] Package with Small Size and Low 1.07 mm Profile
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2002/95/EC

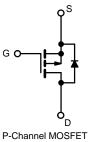
APPLICATIONS

- · Load Switch
- Adaptor Switch
- Notebook PC



DFN 3x3 EP





Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	- 30	v	
Gate-Source Voltage		V _{GS} ± 20		V	
	T _C = 25 °C		- 45		
Continuous Drain Current (T $= 150$ °C)	T _C = 70 °C		- 30		
Continuous Drain Current ($T_J = 150 \ ^{\circ}C$)	T _A = 25 °C		- 14.4 ^{a, b}		
	T _A = 70 °C		- 11.5 ^{a, b}		
Pulsed Drain Current	I _{DM}	- 60	— A		
Continuous Source-Drain Diode Current	T _C = 25 °C	1	- 35 ^e		
	T _A = 25 °C	Is Is	- 3.2 ^{a, b}		
Avalanche Current	L = 0.1 mH		- 25		
Single-Pulse Avalanche Energy		E _{AS}	31.25	mJ	
	T _C = 25 °C		52		
Maximum Bawar Dissipation	T _C = 70 °C	P _D	43	w	
Maximum Power Dissipation	T _A = 25 °C	۲D	3.8 ^{a, b}	VV	
	T _A = 70 °C		2.4 ^{a, b}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 50 to 150		
Soldering Recommendations (Peak Temperature) ^{c, d}			260		

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c.Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.

d.Package limited.

e.Based on T $_{\rm C}$ = 25 °C



T	THERMAL RESISTANCE RATINGS						
Pa	rameter		Symbol	Typical	Maximum	Unit	
Ma	aximum Junction-to-Ambient ^{a, b}	t ≤ 10 s	R _{thJA}	26	33	°C/W	
Ma	aximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.9	2.4	C/W	

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. Maximum under Steady State conditions is 81 °C/W.

Devemeter	Cumela al	Test Conditions	NA:	There.	Marr	11	
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static						I	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = -250 \mu A$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 20		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$	- 1.5		- 2.8	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	μA	
Zere date voltage Brain ourrent	.033	V_{DS} = - 30 V, V_{GS} = 0 V, T_{J} = 55 °C			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le$ - 5 V, V_{GS} = - 10 V	- 20			Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 10 V, I _D = - 14.4 A		11	m		
Dialii-Source Oli-State Resistance	1 (DS(on)	V _{GS} = - 4.5 V, I _D = - 11.5 A		18		11152	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 14.4 A		37		S	
Dynamic ^b							
Input Capacitance	C _{iss}			2000		pF	
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		385			
Reverse Transfer Capacitance	C _{rss}]		322			
Tatal Cata Charge		$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -14.4 \text{ A}$			15	nC	
Total Gate Charge	Q _g				14		
Gate-Source Charge	Q _{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -14.4 \text{ A}$			7		
Gate-Drain Charge	Q _{gd}]			9		
Gate Resistance	R _g	f = 1 MHz	0.4	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			50	75		
Rise Time	t _r	V_{DD} = - 15 V, R_L = 1.5 Ω		43	65	-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		30	45		
Fall Time	t _f			14	21		
Turn-On Delay Time	t _{d(on)}			14	21	ns	
Rise Time	t _r	V_{DD} = - 15 V, R _L = 1.5 Ω		9	18		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		36	54		
Fall Time	t _f	1		10	20	1	
Drain-Source Body Diode Characterist	ics			<u></u>		<u> </u>	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			- 35 ^e		
Pulse Diode Forward Current ^a	I _{SM}				- 60	A	
Body Diode Voltage	V _{SD}	I _F = - 10 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	· · · · · · · · · · · · · · · · · · ·		31	47	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			30	45	nC	
Reverse Recovery Fall Time	ta	$I_F = -10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		15	-		
Reverse Recovery Rise Time	t _b			16		ns	

Notes:

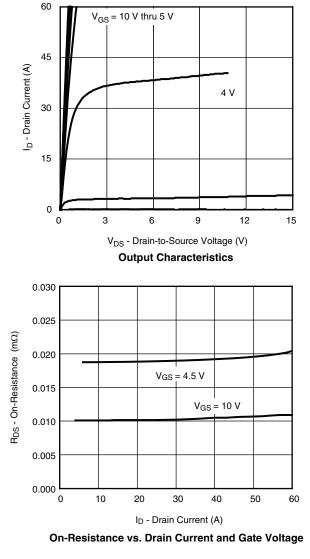
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

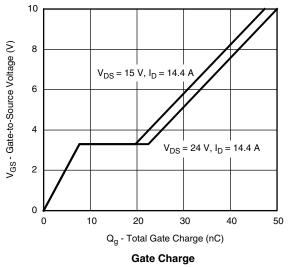
b. Guaranteed by design, not subject to production testing.

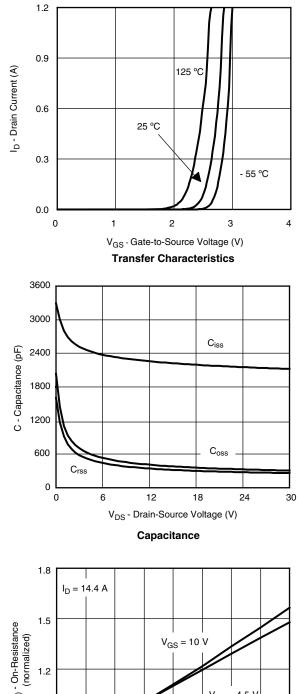
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

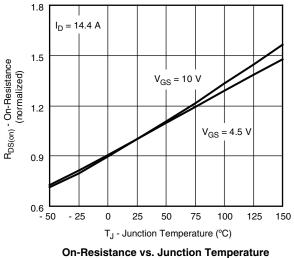


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

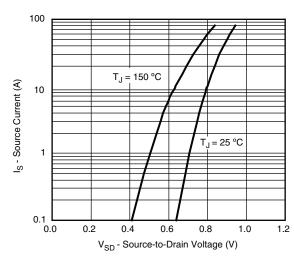




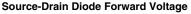


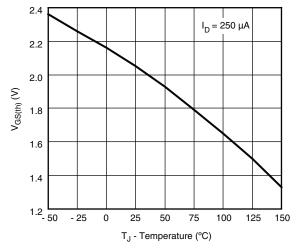




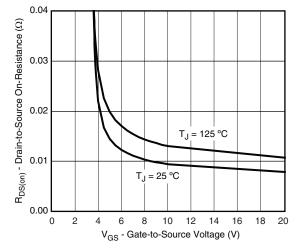


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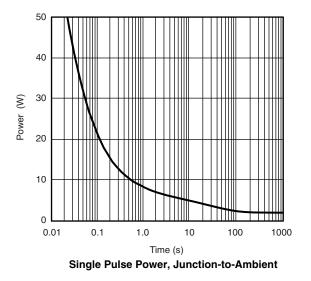


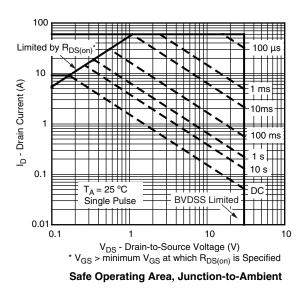






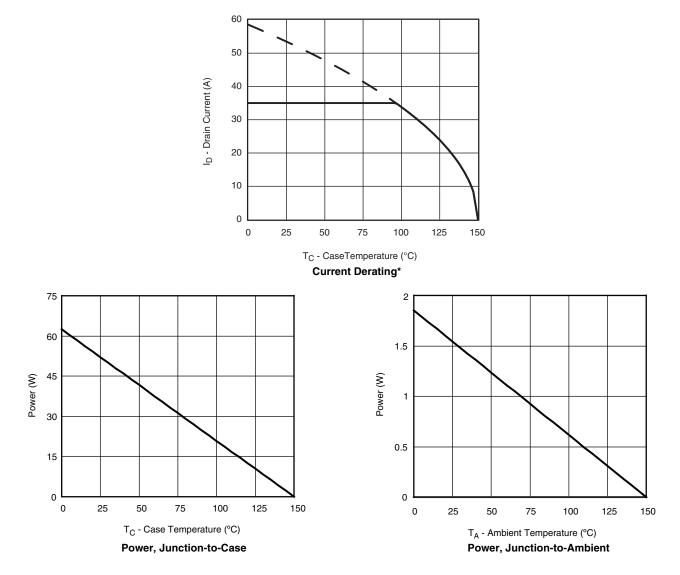
On-Resistance vs. Gate-to-Source Voltage







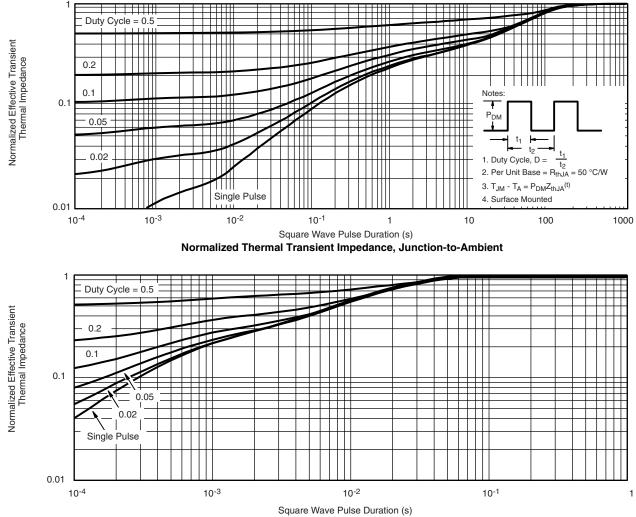
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

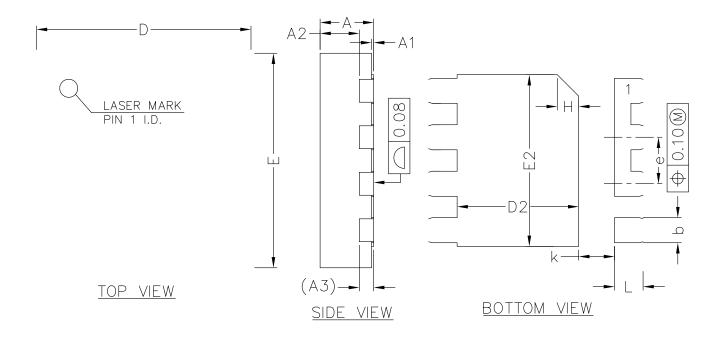






Normalized Thermal Transient Impedance, Junction-to-Case

WBsemi www.VBsemi.com





<u>SIDE VIEW</u>

			,	
SYMBOL	MIN	NOM	MAX	
А	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
A3	0.20REF			
b	0.30	0.35	0.40	
D	2.90	3.00	3.10	
E	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
К	0.40	0.50	0.60	
L	0.35	0.40	0.45	

COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)



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